

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Takashi IGARASHI et al.

Group Art Unit: 3723

Application No.: 10/611,918

Examiner: H. SHAKERI

Filed: July 3, 2003

Docket No.: 108833.01

For: LENS MACHINING APPARATUS, LENS MACHINING METHOD, AND LENS MEASUREMENT METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection, Notice of Allowance, or other action that closes prosecution (e.g., Quayle Action), but before payment of the Issue Fee. The fees associated with this filing under 37 C.F.R. §1.17(i) are being paid electronically with this filing. The Commissioner is hereby authorized to charge any additional fee (or credit any overpayment) associated with this communication to Deposit Account No. 15-0461.
- ☒ a. I hereby certify that no item of information in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR §1.56(e) more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(2).
- ☒ 2. One or more reference cited herein was cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information. See References 3-8.

- ☒ 3. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 4. An English language Abstract of one or more non-English language reference is attached hereto. See References 3-8.
- ☒ 5. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 3, 4, 6 and 7.
- ☒ 6. References 1 and 2 correspond to references 4 and 5, respectively.
- ☒ 7. U.S. Patent No. 6,050,877, which is the U.S. family member of Reference 3, was previously disclosed in the Information Disclosure Statement filed July 3, 2003.

Respectfully submitted,

Leana Levin

James A. Oliff
Registration No. 27,075

Leana Levin
Registration No. 51,939

JAO:LL/can

Date: November 21, 2006

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

<p>DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461</p>

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PATENT & TRADEMARK OFFICEATTY DOCKET NO.
108833.01APPLICATION NO.
10/611,918

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)
Takashi IGARASHI et al.FILING DATE
July 3, 2003GROUP
3723

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name
	1	6,059,635	5/9/2000	Mizuno
	2	4,772,160	9/20/1988	Barwasser

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
	3	JP 10-138109	5/26/1998	Japan	X	X
	4	JP 10-296602	11/10/1998	Japan	X	X
	5	JP 62-292354	12/19/1987	Japan	X	
	6	JP 05-345268	12/27/1993	Japan	X	X
	7	JP 06-055324	3/1/1994	Japan	X	X
	8	JP 61-014849	1/23/1986	Japan	X	

OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: November 21, 2006